

Substitute for Form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known		
				Application Number	N/A	
				Filing Date	Herewith	
				First Named Inventor:	Zorian	
				Art Unit	N/A	
				Examiner Name	Unassigned	
				Attorney Docket Number	04640.P019	
Sheet	1	of	2			
U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)				
JK ↓ V		US-	5,513,318	04/30/1996	Van de Goor, et al.	
		US-	5,960,009	09/28/1999	Gizopoulos, et al.	
		US-	5,978,935	11/02/1999	Kim, et al.	
		US-	5,978,947	11/02/1999	Kim, et al.	
		US-	6,330,696 B1	12/11/2001	Zorian, et al.	
		US-	6,397,349 B2	05/28/2002	Higgins, et al.	
		US-	6,237,123 B1	05/22/2001	Kim, et al.	
		US-	6,205,564 B1	05/20/2001	Kim, et al.	
		US-	6,085,334	07/04/2000	Giles, et al.	
		US-	6,317,846 B1	11/13/2001	Higgins, et al.	
		US-	5,570,374	10/29/1996	Yau, et al.	
		US-				
	US-					
	US-					
	US-					

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)				

Examiner Signature	/James Kerveros/	Date Considered	08/31/2006
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Sheet	2	of	2	Attorney Docket Number	04640.P019
NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T ²
JK		Yervant Zorian: "System-Chip Test Strategies" (Tutorial): DAC 1998: 752-757.			
		Ilyoung Kim, Yervant Zorian, Goh Komoriya, Hai Pham, Frank P. Higgins, Jim L. Lewandowski: " Built-in Self-Repair for Embedded High Density SRAM." ITC 1998: 1112-1119			
		Yervant Zorian, Erik Jan Marinissen, Sujit Dey: "Testing Embedded-Core Based System Chips." ITC 1998: pages 1-14			
		Yervant Zorian, Erik Jan Marinissen, "System Chip Test: How Will It Impact Your Design?", DAC, 2000, pages 1-6.			
		Monica Lobetti Bodoni, Alfredo Benso, Silvia Chiusano, Stefano DiCarlo, Giorgio DiNatale, Paolo Prinetto, "An Effective Distributed BIST Architecture for RAMs," pages 1-6, IEEE European Test Workshop, 2000.			
		Chauchin Su, Shih-Ching Hsiao, Hau-Zen Zhou, Chung-Len Lee, "A Computer Aided Engineering System for Memory BIST," DAC, 2001 pages 1-4.			
		Yervant Zorian, "Embedding Infrastructure IP for SOC Yield Improvement," June 2002, 709-712.			
		Praveen Parvathala, Kailas Maneparambil, William Lindsay, "FRITS – A Microprocessor Functional BIST Method," ITC, Mar. 2002, pages 590-598.			
		TechWeb definition, AUTHOR UNKNOWN, scan technology, copyright 1981-2001, 1 page.			
		S. Shoukourian, V. Vardanian, Y. Zorian, "An Approach for Evaluation of Redundancy Analysis Algorithms," The Proceedings of IEEE Int. Workshop on Memory Technology, Design and Testing, 2001.			
		D.K. Bhavsar, "An Algorithm for Row-Column Self-Repair of RAMs and its Implementation in the Alpha 21264," Proc. ITC'1999, pp. 311-318.			
↓		T. Kawagoe, J. Ohtani, M. Niino, T. Oishi, M. Hamada, H. Hidaka, "A Built-In Self-Repair Analyzer (CRESTA) for Embedded DRAMs," Proc. ITC'2000, pp. 567-574.			

Examiner Signature	/James Kerveros/	Date Considered	08/31/2006
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